

December 2011

FDZ661PZ

P-Channel 1.5 V Specified PowerTrench[®] Thin WL-CSP MOSFET -20 V, -2.6 A, 140 m Ω

Features

- Max $r_{DS(on)}$ = 140 m Ω at V_{GS} = -4.5 V, I_D = -2 A
- Max $r_{DS(on)} = 182 \text{ m}\Omega$ at $V_{GS} = -2.5 \text{ V}$, $I_D = -1.5 \text{ A}$
- Max $r_{DS(on)}$ = 231 m Ω at V_{GS} = -1.8 V, I_D = -1 A
- Max $r_{DS(on)}$ = 315 m Ω at V_{GS} = -1.5 V, I_D = -1 A
- Occupies only 0.64 mm² of PCB area. Less than 16% of the area of 2 x 2 BGA
- Ultra-thin package: less than 0.4 mm height when mounted to PCB
- HBM ESD protection level > 2 kV (Note3)
- RoHS Compliant

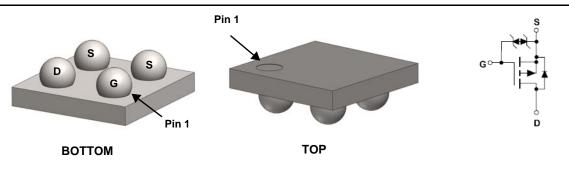


General Description

Designed on Fairchild's advanced 1.5 V PowerTrench[®] process with state of the art "fine pitch" Thin WLCSP packaging process, the FDZ661PZ minimizes both PCB space and $r_{DS(on)}.$ This advanced WLCSP MOSFET embodies a breakthrough in packaging technology which enables the device to combine excellent thermal transfer characteristics, ultra-low profile (0.4 mm) and small (0.8x0.8 mm²) packaging, low gate charge, and low $r_{DS(on)}.$

Applications

- Battery management
- Load switch
- Battery protection



WL-CSP 0.8X0.8 Thin

MOSFET Maximum Ratings T_A = 25 °C unless otherwise noted

Symbol	Param		Ratings	Units	
V _{DS}	Drain to Source Voltage			-20	V
V_{GS}	Gate to Source Voltage			±8	V
	-Continuous	T _A = 25 °C	(Note 1a)	-2.6	۸
'D	-Pulsed			-10	_ A
D	Power Dissipation	T _A = 25 °C	(Note 1a)	1.3	W
P_{D}	Power Dissipation	T _A = 25 °C	(Note 1b)	0.4	VV
T _J , T _{STG}	Operating and Storage Junction Temperature Range			-55 to +150	°C

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1a)	93	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1b)	311	C/VV

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
EH	FDZ661PZ	WL-CSP 0.8X0.8 Thin	7 "	8 mm	5000 units

©2011 Fairchild Semiconductor Corporation FDZ661PZ Rev.C

Electrical Characteristics T_J = 25 °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	acteristics					
BV _{DSS}	Drain to Source Breakdown Voltage	$I_D = -250 \mu A, V_{GS} = 0 V$	-20			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I_D = -250 μA, referenced to 25 °C		-13		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = -16 V, V _{GS} = 0 V			-1	μΑ
I_{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 8 \text{ V}, V_{DS} = 0 \text{ V}$			±6	μΑ

On Characteristics

$V_{GS(th)}$	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = -250 \mu A$	-0.3	-0.7	-1.2	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I_D = -250 μ A, referenced to 25 °C		2.5		mV/°C
		$V_{GS} = -4.5 \text{ V}, I_D = -2 \text{ A}$		108	140	
		$V_{GS} = -2.5 \text{ V}, I_D = -1.5 \text{ A}$		129	182	
r _{DS(on)}	Static Drain to Source On Resistance	$V_{GS} = -1.8 \text{ V}, I_D = -1 \text{ A}$		159	231	mΩ
		$V_{GS} = -1.5 \text{ V}, I_D = -1 \text{ A}$		201	315	
		$V_{GS} = -4.5 \text{ V}, I_D = -2 \text{ A}, T_J = 125 ^{\circ}\text{C}$		143	204	
9 _{FS}	Forward Transconductance	$V_{DD} = -5 \text{ V}, I_D = -2 \text{ A}$		7.8		S

Dynamic Characteristics

C _{iss}	Input Capacitance	V 40 V V 0 V	416	555	pF
C _{oss}	Output Capacitance	$V_{DS} = -10 \text{ V}, V_{GS} = 0 \text{ V},$ $f = 1 \text{ MHz}$	61	80	pF
C _{rss}	Reverse Transfer Capacitance	1 - 1 101112	53	70	pF

Switching Characteristics

	•				
t _{d(on)}	Turn-On Delay Time		4.9	10	ns
t _r	Rise Time	$V_{DD} = -10 \text{ V}, I_D = -2.5 \text{ A},$	6.3	13	ns
t _{d(off)}	Turn-Off Delay Time	$V_{GS} = -4.5 \text{ V}, R_{GEN} = 6 \Omega$	68	108	ns
t _f	Fall Time		33	52	ns
Q_g	Total Gate Charge	V 45VV 40V	6.3	8.8	nC
Q _{gs}	Gate to Source Charge	$V_{GS} = -4.5 \text{ V}, V_{DD} = -10 \text{ V},$ $I_{D} = -2.5 \text{ A}$	0.6		nC
Q_{gd}	Gate to Drain "Miller" Charge	1D = 2.0 A	1.7		nC

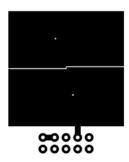
Drain-Source Diode Characteristics

V_{SD}	Source to Drain Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = -1.4 \text{ A}$ (Note 2)	-0.9	-1.2	V
t _{rr}	Reverse Recovery Time	I _F = -2.5 A, di/dt = 100 A/μs	29	46	ns
Q _{rr}	Reverse Recovery Charge	T _F = -2.5 A, α/αι = 100 A/μs	10	18	nC

Notes:

Notes.

1. R_{0,JA} is determined with the device mounted on a 1 in² pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R_{0,JC} is guaranteed by design while R_{0,CA} is determined by the user's board design.



a. 93 °C/W when mounted on a 1 in² pad of 2 oz copper.



b. 311 °C/W when mounted on a minimum pad of 2 oz copper.

- 2. Pulse Test: Pulse Width < 300 μ s, Duty cycle < 2.0%.
- 3. The diode connected between the gate and source serves only as protection ESD. No gate overvoltage rating is implied.

Typical Characteristics T_J = 25 °C unless otherwise noted

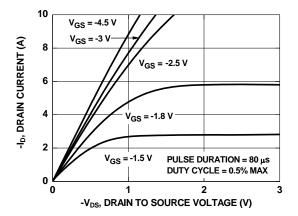


Figure 1. On-Region Characteristics

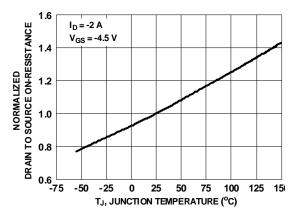


Figure 3. Normalized On-Resistance vs Junction Temperature

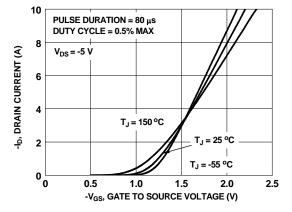


Figure 5. Transfer Characteristics

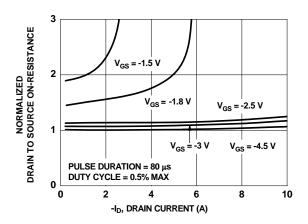


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

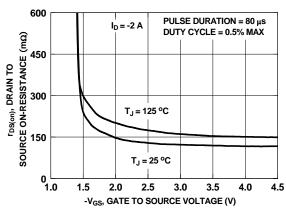


Figure 4. On-Resistance vs Gate to Source Voltage

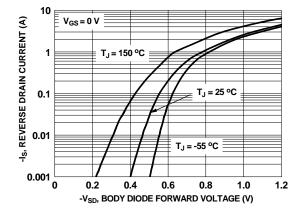


Figure 6. Source to Drain Diode Forward Voltage vs Source Current



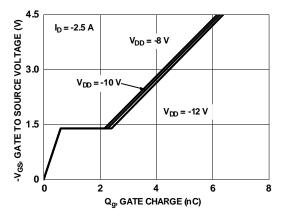


Figure 7. Gate Charge Characteristics

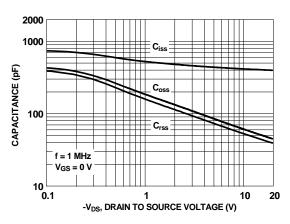


Figure 8. Capacitance vs Drain to Source Voltage

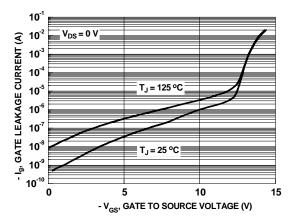


Figure 9. Gate Leakage Current vs Gate to Source Voltage

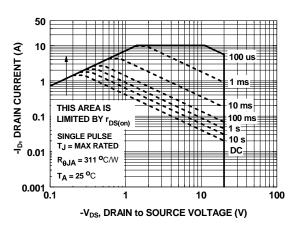


Figure 10. Forward Bias Safe Operating Area

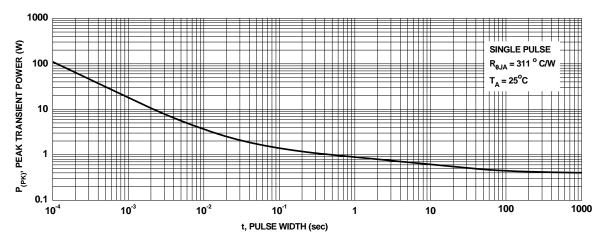


Figure 11. Single Pulse Maximum Power Dissipation

Typical Characteristics $T_J = 25$ °C unless otherwise noted

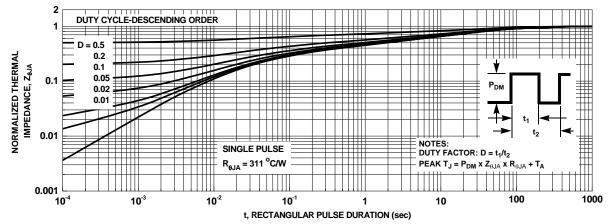
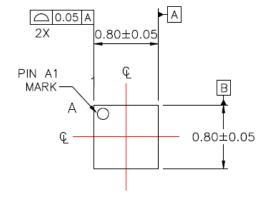
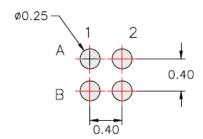


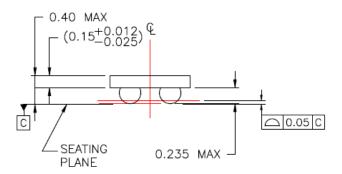
Figure 12. Junction-to-Ambient Transient Thermal Response Curve

Dimensional Outline and Pad Layout

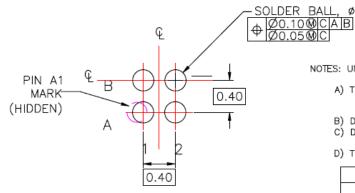




○ 0.05 B



LAND PATTERN RECOMMENDATION



NOTES: UNLESS OTHERWISE SPECIFIED

Ø0.265±0.025

- A) THIS PACKAGE IS NOT PRESENTLY REGISTERED WITH ANY STANDARDS COMMITTEE.
- B) DIMENSIONS ARE IN MILLIMETERS.
- C) DRAWING CONFORMS TO ASME Y14.5M-1994
- D) TERMINAL CONFIGURATION TABLE:

GATE	SOURCE	DRAIN
A1	A2, B2	B1



TRADEMARKS

The following includes registered and unregistered trademarks and service marks, owned by Fairchild Semiconductor and/or its global subsidiaries, and is not intended to be an exhaustive list of all such trademarks.

2Cool™ **FPSTM** F-PFS™ AccuPower™ FRFET® Auto-SPM™ Global Power ResourceSM

AX-CAP™* BitSiC® GreenBridge™ Green FPS™ Build it Now™ Green FPS™ e-Series™ CorePLUS™

CorePOWER™ Gmax™ GTO™ CROSSVOLT™ CTL™ IntelliMAX™ Current Transfer Logic™ ISOPLANAR™

DEUXPEED® Marking Small Speakers Sound Louder and Better™

MegaBuck™

MicroFET™

MicroPak™ MicroPak2™

MillerDrive™

MotionMax™

mWSaver™

OptoHiT™

Motion-SPM™

OPTOLOGIC®

OPTOPLANAR®

MICROCOUPLER™

Dual Cool™ EcoSPARK® EfficentMax™ ESBC™

Fairchild[®] Fairchild Semiconductor® FACT Quiet Series™

FACT® FAST® FastvCore™ FETBench™ PowerTrench® PowerXS™

Programmable Active Droop™

QFET® QSTM

Quiet Series™ RapidConfigure™

Saving our world, 1mW/W/kW at a time™

SignalWise™ SmartMax™ SMART START™

Solutions for Your Success™

STEALTH™ SuperFET® SuperSOT™-3 SuperSOT™-6 SuperSOT™-8 SupreMOS® SyncFET™ Sync-Lock™

SYSTEM ®*

The Power Franchise® wer franchise TinyBoost™ TinyBuck™ TinyCalc™ TinyLogic[®] TINYOPTO™ TinyPower™ TinvPWM™ TinyWire™ TranSiC[®] TriFault Detect™ TRUECURRENT®* μSerDes™ UHC® Ultra FRFET™ UniFET™ VCX™ VisualMax™ VoltagePlus™

XSTM

*Trademarks of System General Corporation, used under license by Fairchild Semiconductor.

DISCLAIMER

FAIRCHILD SEMICONDUCTOR RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION, OR DESIGN. FAIRCHILD DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS, NOR THE RIGHTS OF OTHERS. THESE SPECIFICATIONS DO NOT EXPAND THE TERMS OF FAIRCHILD'S WORLDWIDE TERMS AND CONDITIONS, SPECIFICALLY THE WARRANTY THEREIN, WHICH COVERS THESE PRODUCTS.

LIFE SUPPORT POLICY
FAIRCHILD'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF FAIRCHILD SEMICONDUCTOR CORPORATION.

- Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body or (b) support or sustain life, and (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in a significant injury of the user.
- A critical component in any component of a life support, device, or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness

ANTI-COUNTERFEITING POLICY

Fairchild Semiconductor Corporation's Anti-Counterfeiting Policy. Fairchild's Anti-Counterfeiting Policy is also stated on our external website, www.Fairchildsemi.com, under Sales Support.

Counterfeiting of semiconductor parts is a growing problem in the industry. All manufactures of semiconductor products are experiencing counterfeiting of their parts. Customers who inadvertently purchase counterfeit parts experience many problems such as loss of brand reputation, substandard performance, failed application, and increased cost of production and manufacturing delays. Fairchild is taking strong measures to protect ourselves and our customers from the proliferation of counterfeit parts. Fairchild strongly encourages customers to purchase Fairchild parts either directly from Fairchild or from Authorized Fairchild Distributors who are listed by country on our web page cited above. Products customers buy either from Fairchild directly or from Authorized Fairchild Distributors are genuine parts, have full traceability, meet Fairchild's quality standards for handing and storage and provide access to Fairchild's full range of up-to-date technical and product information. Fairchild and our Authorized Distributors will stand behind all warranties and will appropriately address and warranty issues that may arise. Fairchild will not provide any warranty coverage or other assistance for parts bought from Unauthorized Sources. Fairchild is committed to combat this global problem and encourage our customers to do their part in stopping this practice by buying direct or from authorized distributors.

PRODUCT STATUS DEFINITIONS Definition of Terms

Datasheet Identification	Product Status	Definition
Advance Information	Formative / In Design	Datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
Preliminary	First Production	Datasheet contains preliminary data; supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve design.
No Identification Needed	Full Production	Datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve the design.
Obsolete	Not In Production	Datasheet contains specifications on a product that is discontinued by Fairchild Semiconductor. The datasheet is for reference information only.
		Rev I6